

Supporting Information: NH₃-induced Activation of Hydrophilic Fe-N-C Nanocages for Enhanced Oxygen Reduction Reaction

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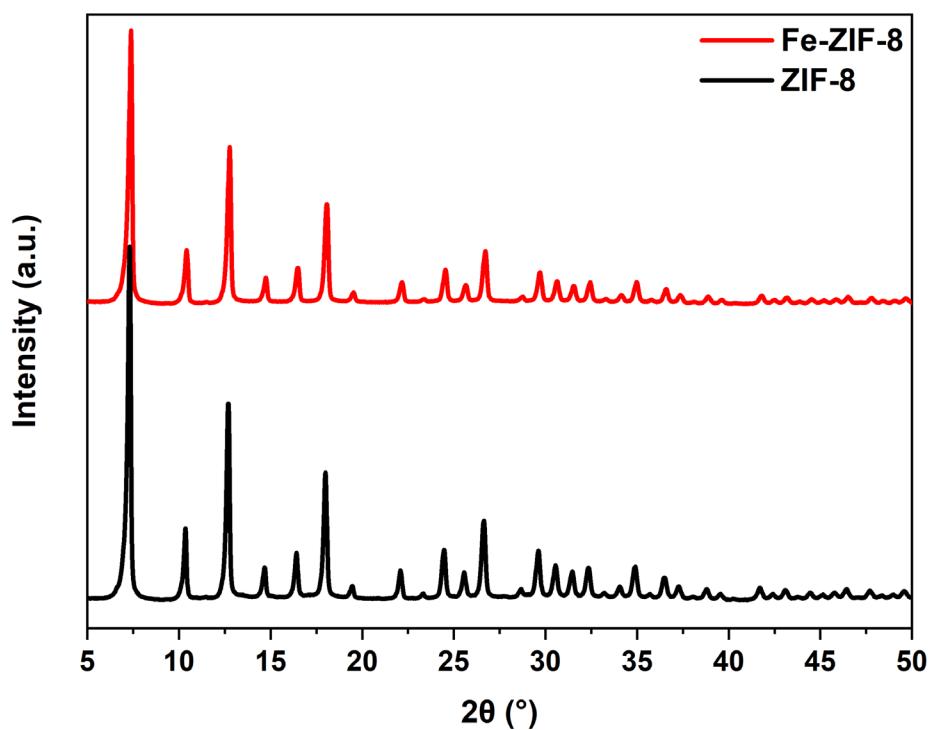


Fig. S1 XRD pattern of ZIF-8 and Fe-ZIF-8.

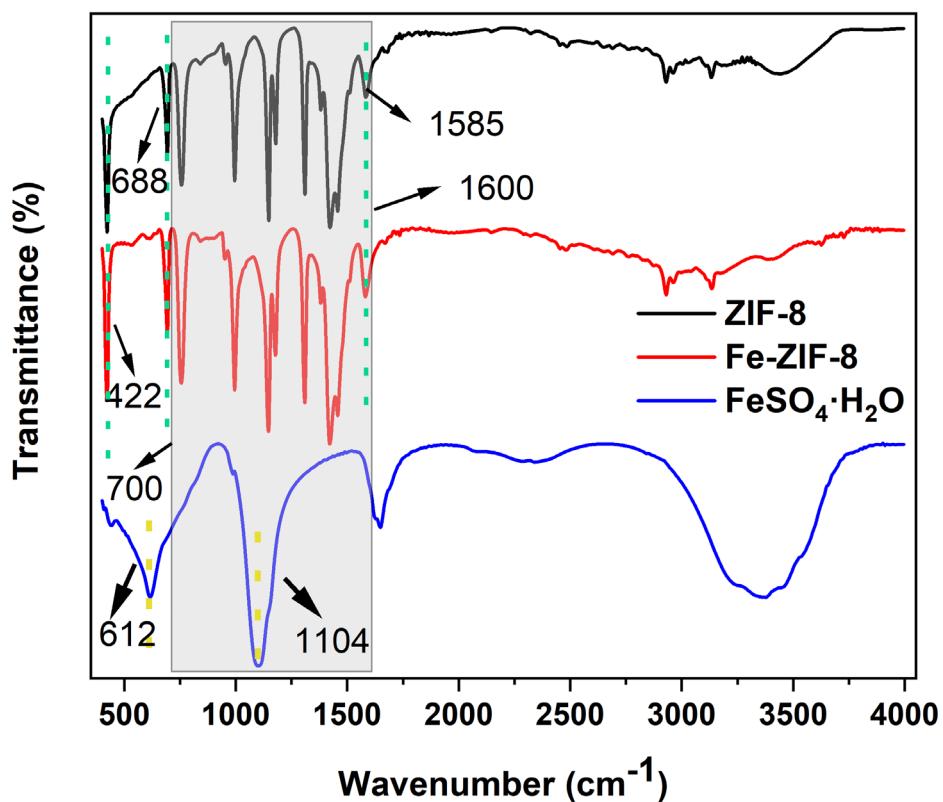


Fig. S2 FTIR spectra of $\text{FeSO}_4 \cdot 7\text{H}_2\text{O}$, ZIF-8 and Fe-ZIF-8.

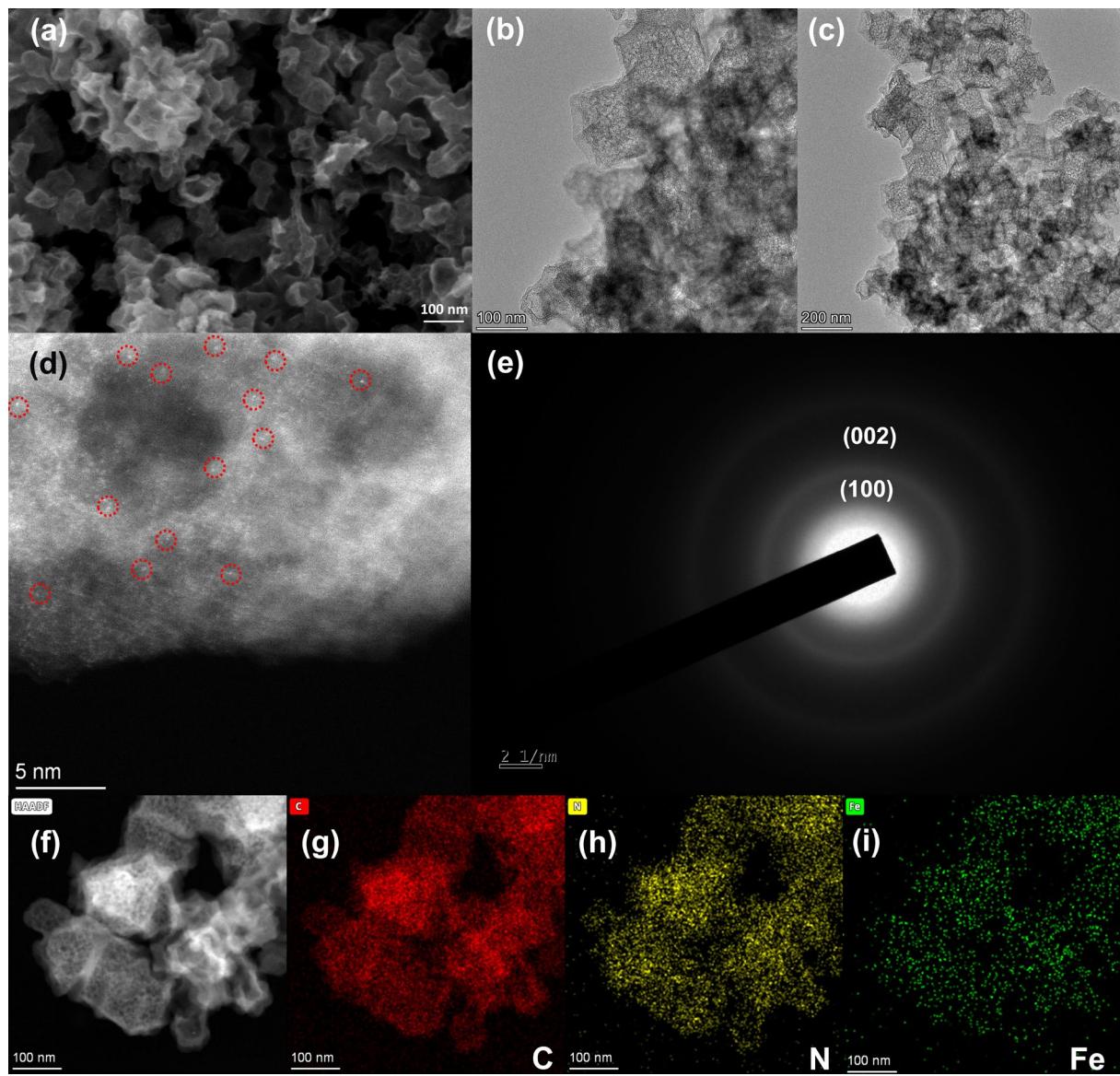


Fig. S3 (a) SEM image of Fe-N-C Ar. (b)-(c) TEM image of Fe-N-C Ar. (d) Aberration-corrected HAADF-STEM image of Fe-N-C Ar. (e) SAED pattern of Fe-N-C Ar. (f)-(i) Elemental mapping analysis of C, N, and Fe of Fe-N-C Ar by HAADF-STEM.

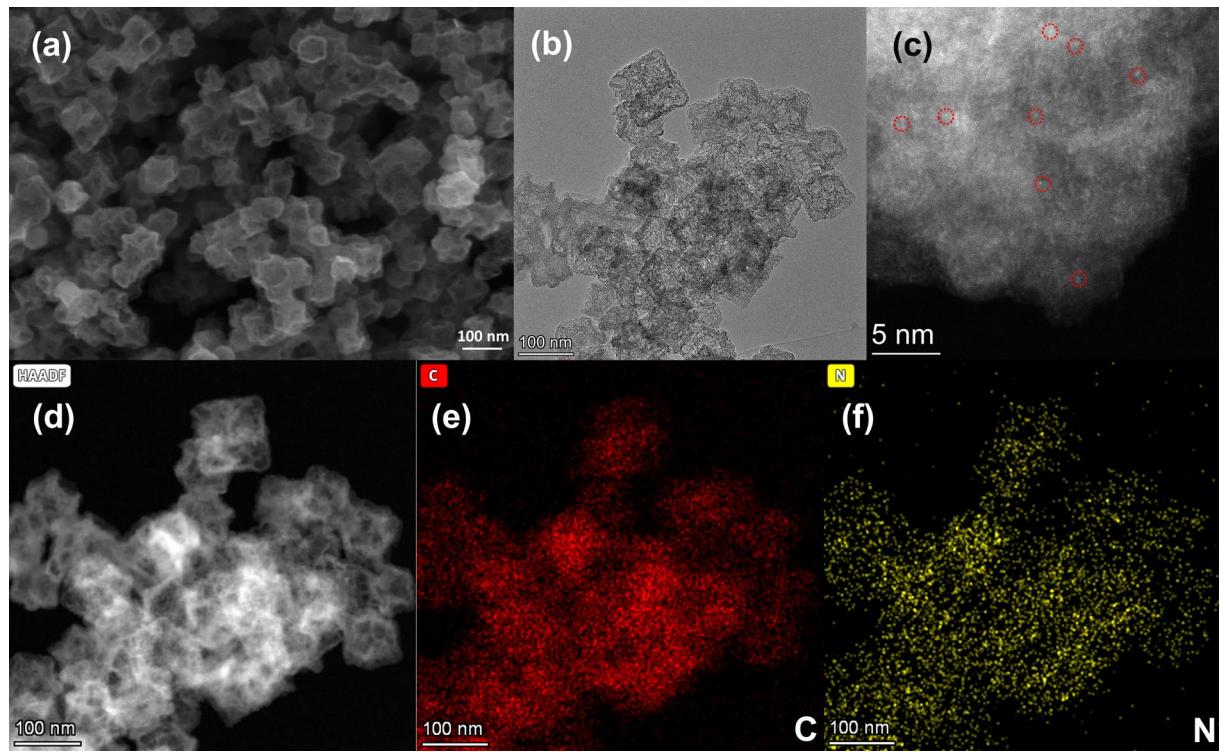


Fig. S4 (a) SEM image of pure NC. (b) TEM image of pure NC. (c) Aberration-corrected HAADF-STEM image of pure NC. (d) SAED pattern of Fe-N-C Ar. (e)-(f) Elemental mapping analysis of C and N of pure NC Ar by HAADF-STEM.

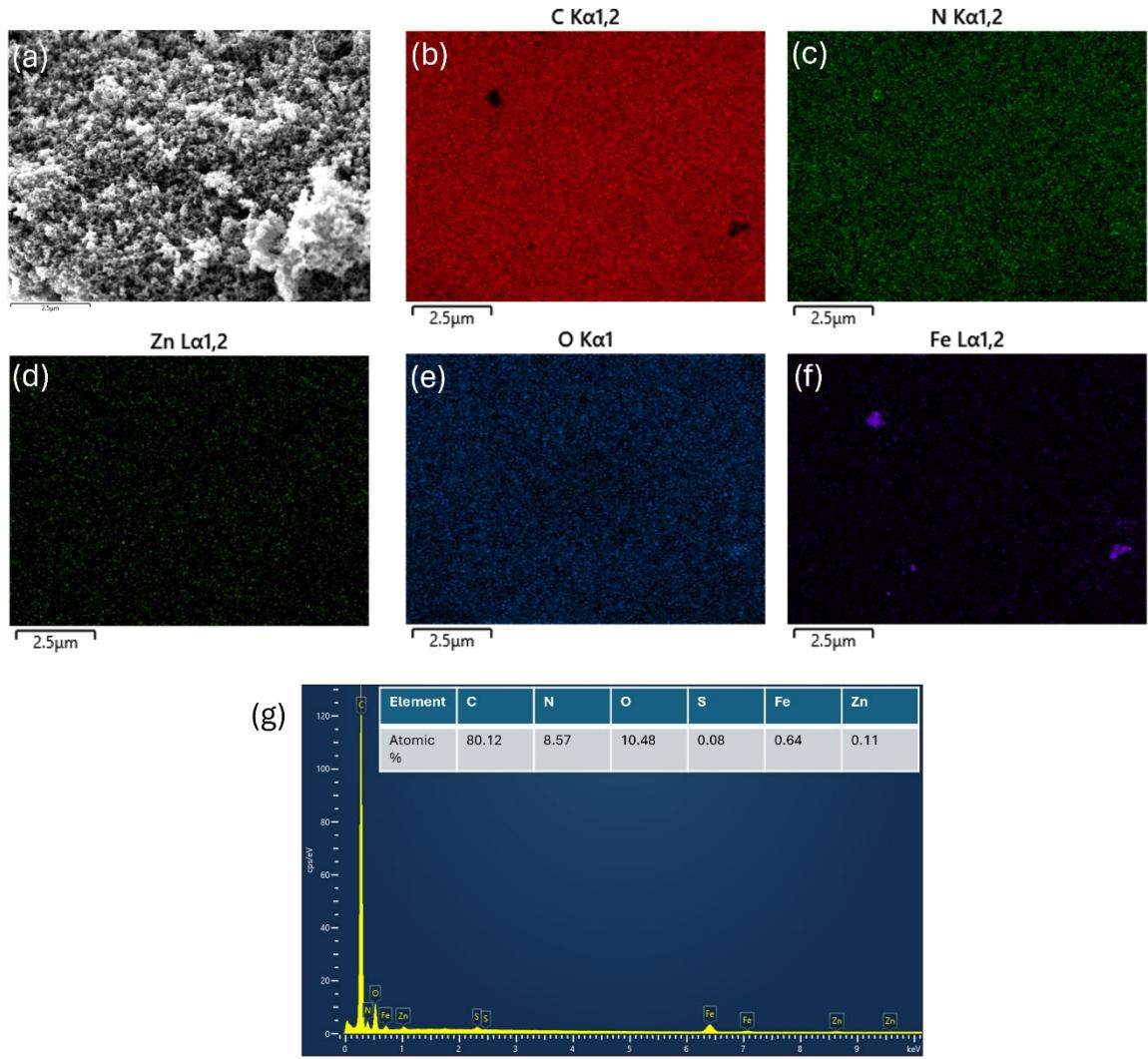


Fig. S5 (a) SEM image of Fe-N-C NH₃. (b-f) Elemental mapping by SEM-EDS. (g) Elemental quantification based on EDS.

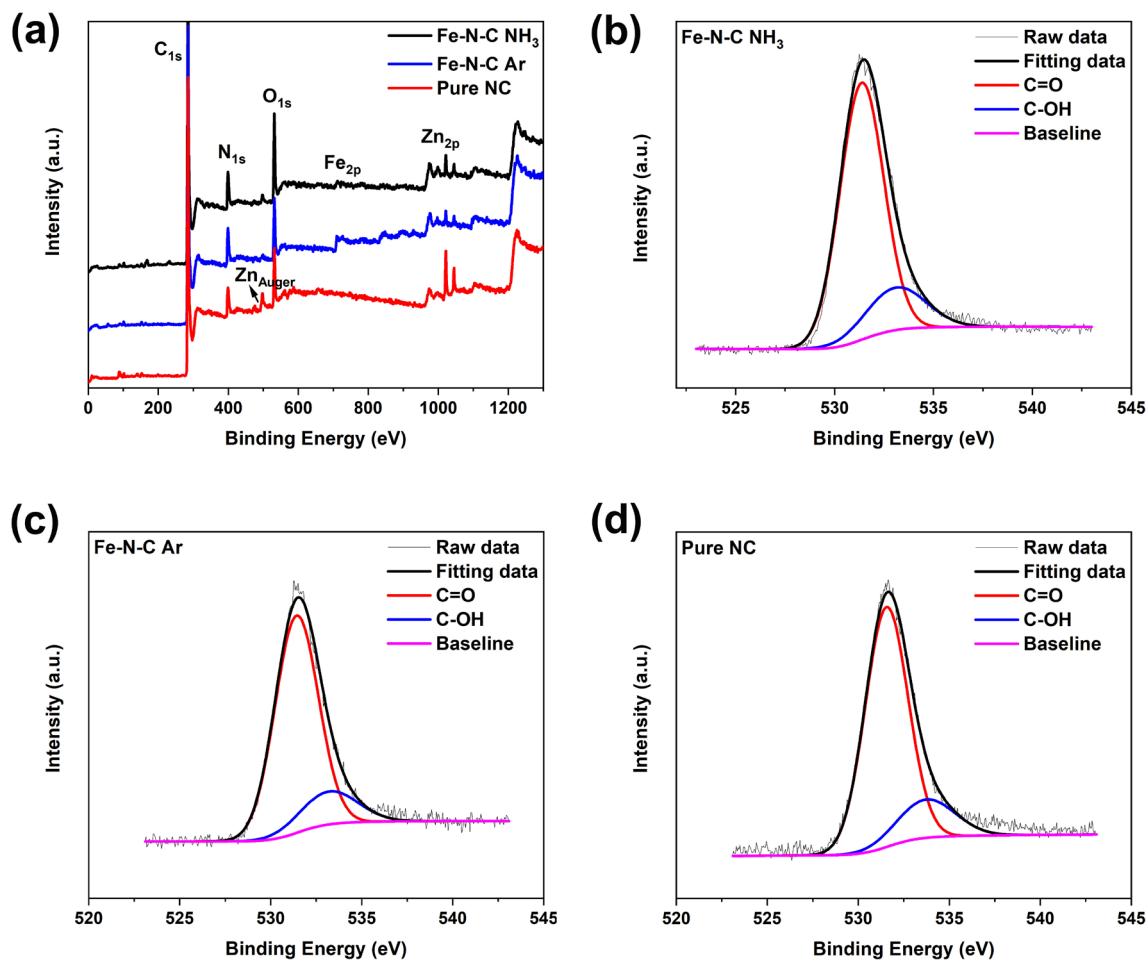


Fig. S6 (a) Overall XPS survey spectra of Fe-N-C NH₃, Fe-N-C Ar and pure NC. (b)-(d) High-resolution O 1s XPS spectra of Fe-N-C NH₃, Fe-N-C Ar and pure NC, respectively.

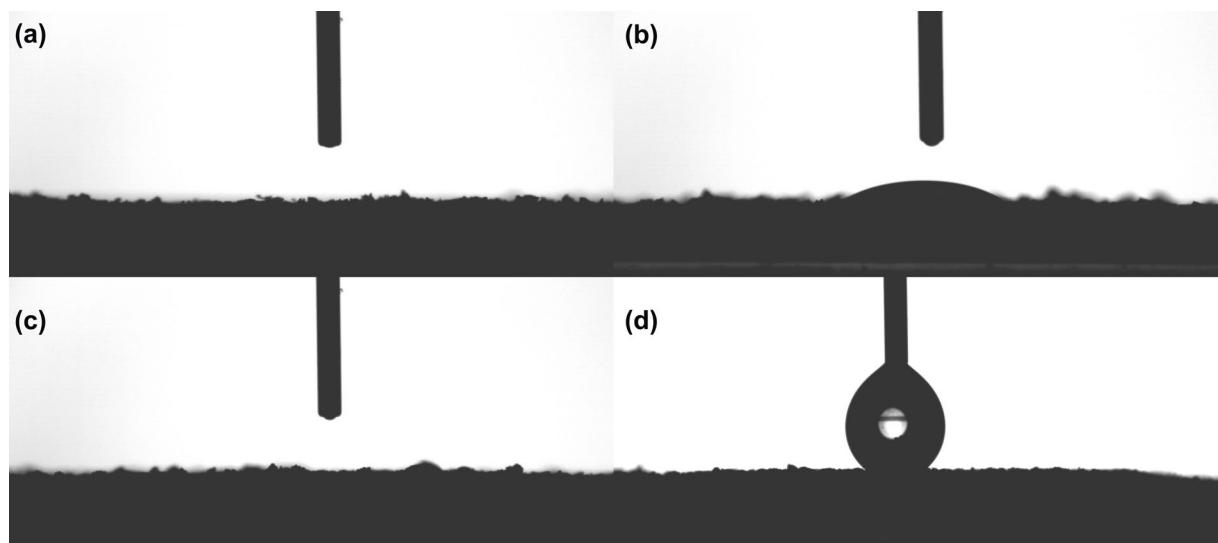


Fig. S7 Contact angle of Fe-N-C NH₃ (a), pure NC (b), Fe-N-C Ar (c) and commercial Pt/C 20% (d).

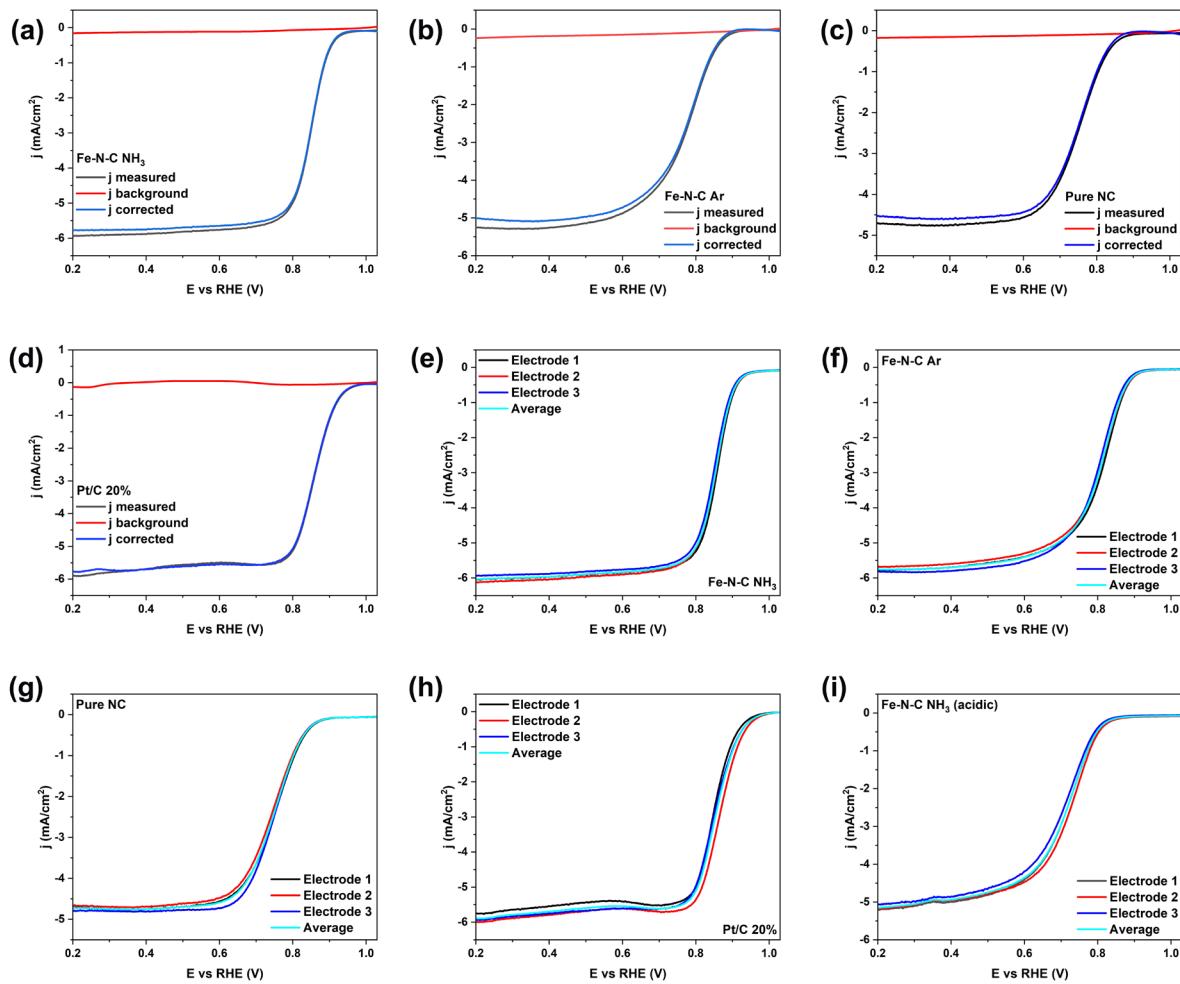


Fig. S8 (a)-(d) ORR voltammograms of Fe-N-C NH₃ (black) recorded in O₂-saturated 0.1 M KOH solution at a scan rate of 5 mV s⁻¹ and electrode rotation of 1600 rpm after background-correction (blue) of Fe-N-C NH₃, Fe-N-C Ar, pure NC and Pt/C 20%, respectively; (red) background current recorded in Ar-saturated 0.1 M NaOH electrolyte with the same measuring conditions. (e)-(i) Reproducibility of voltammetric measurements collected with Fe-N-C NH₃, Fe-N-C Ar, pure NC, Pt/C 20% and Fe-N-C NH₃ in O₂-saturated 0.1 M KOH and in acidic media (0.5 M H₂SO₄) at a scan rate of 5 mV s⁻¹ at 1600 rpm electrode rotation.

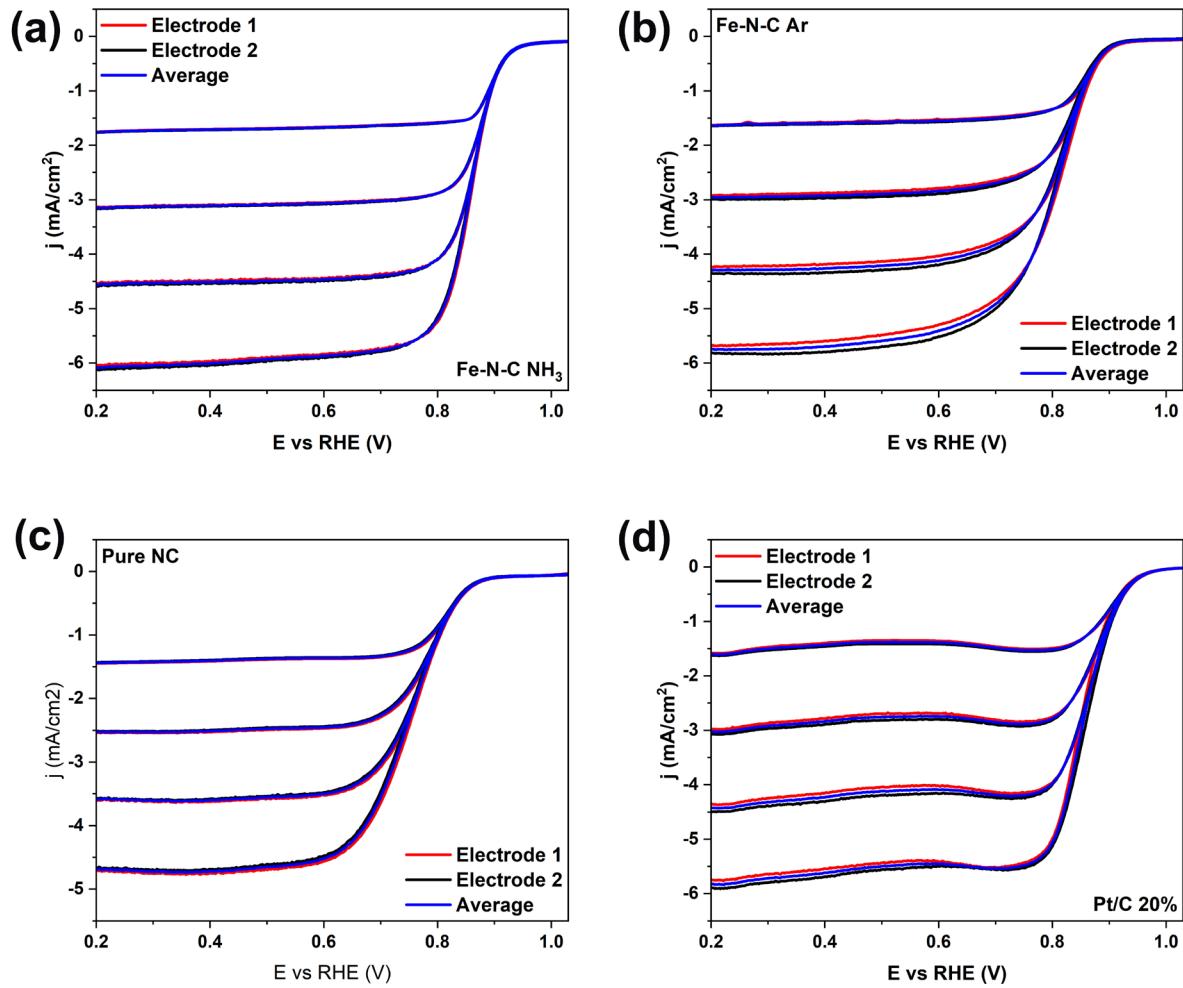


Fig. S9 (a)-(d) Reproducibility of voltametric measurements collected with Fe-N-C NH₃, Fe-N-C Ar, pure NC and Pt/C 20% in O₂-saturated 0.1 M KOH at a scan rate of 5 mV s⁻¹ with different electrode rotations.

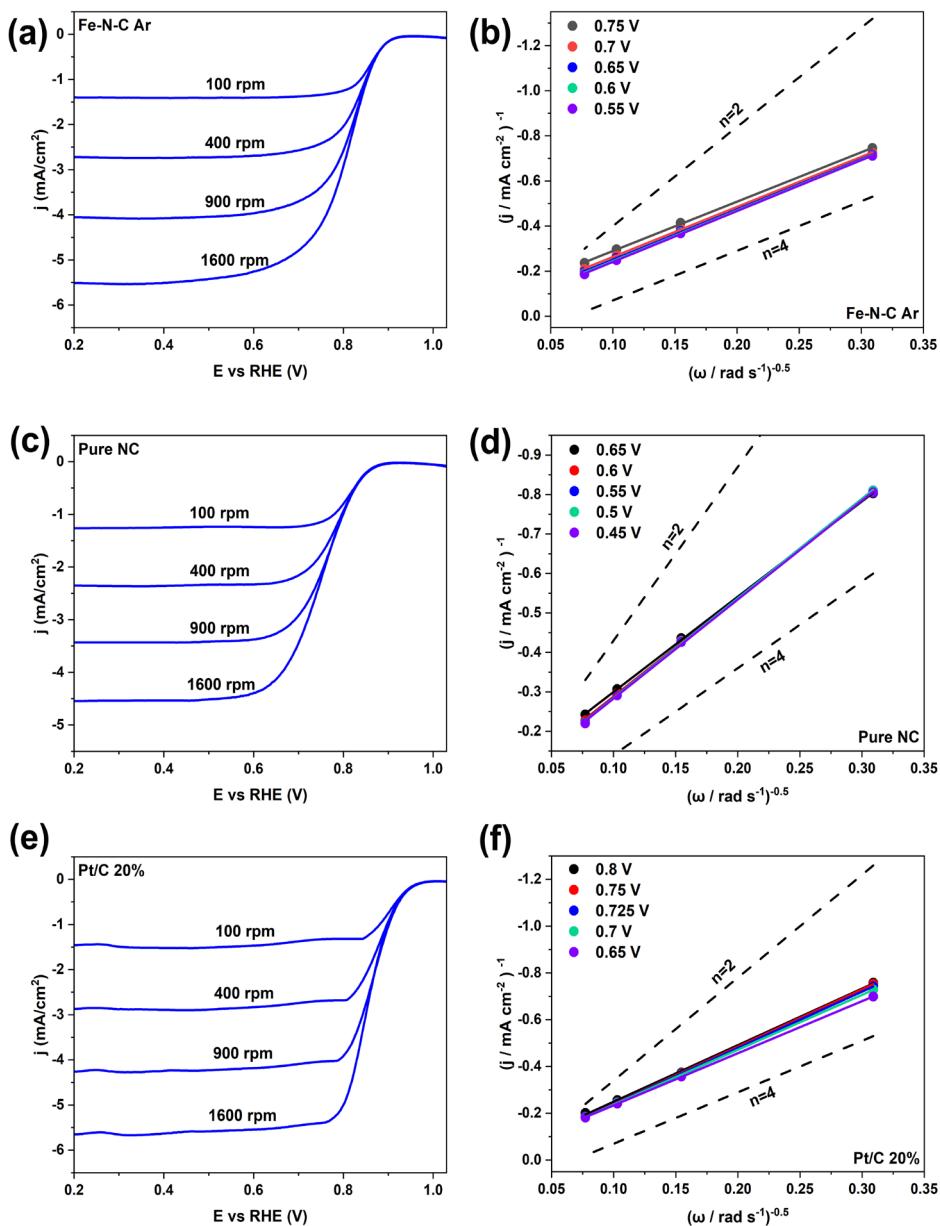


Fig. S10 Background-corrected linear sweep voltammograms recorded at a scan rate of 5 mV s⁻¹ with electrode rotation rates of 100, 400, 900 and 1600 rpm of Fe-N-C Ar (a), pure NC (c) and Pt/C 20% (e). The fitted Koutecky-Levich plots at different electrode potentials for the determination of the number of electrons transferred (n) of Fe-N-C Ar (b), pure NC (d) and Pt/C 20% (f); plots corresponding to the theoretical n=2 and n=4 are shown to facilitate visual comparison. All measurements were conducted using an O₂-saturated 0.1 M KOH solution as electrolyte.

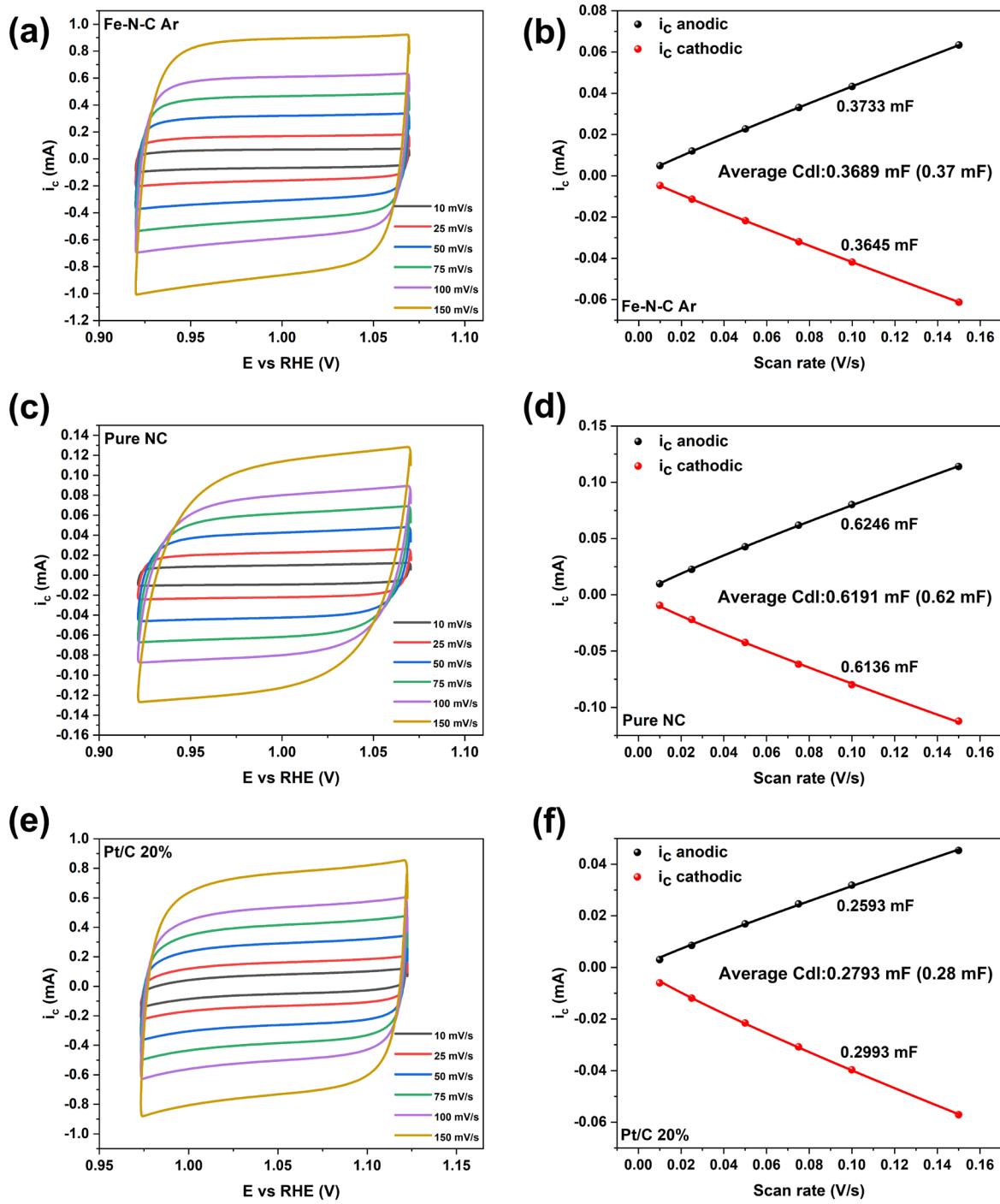


Fig. S11 Cyclic voltammograms recorded at different scan rates from 10 to 150 mV s⁻¹ in the potential range of 0.9 to 1.1 V vs RHE for Fe-N-C Ar (a), pure NC (c) and Pt/C 20% (e). The extraction of the C_{dl} using an allometric function of Fe-N-C Ar (b), pure NC (d) and Pt/C 20% (f). Fit parameters can be found in Table S2.

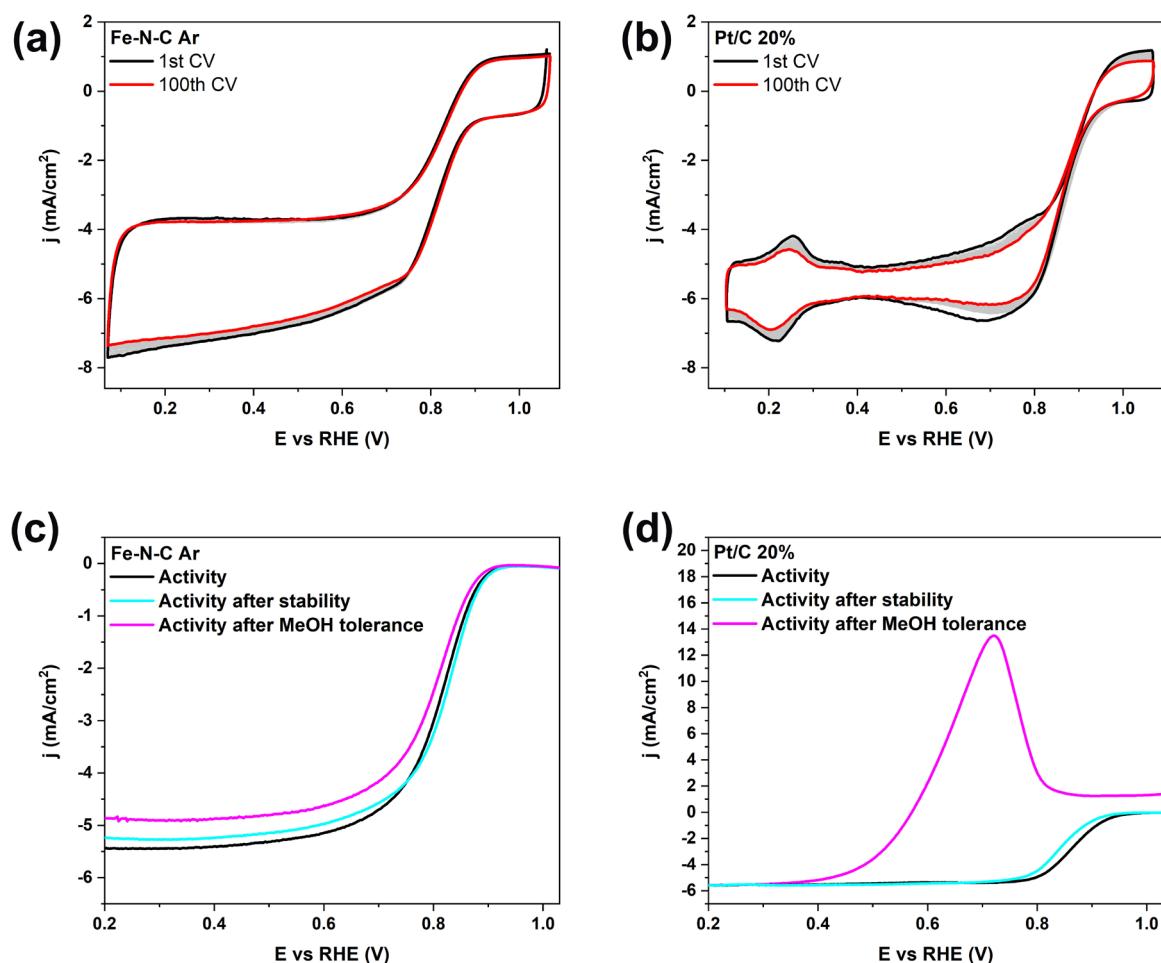


Fig. S12 Stability test recording 100 cyclic voltammograms at scan rate of 50 mV s^{-1} of Fe-N-C Ar (a) and Pt/C 20% (b). ORR activity plots before and after stability test and methanol tolerance in O_2 -saturated 0.1 M KOH of Fe-N-C Ar (c) and Pt/C 20% (d).

Table S1 The XPS atomic content of each element for Fe-N-C NH₃, Fe-N-C Ar and pure NC. The error is typically of +/- 0.5 at% but Fe atoms are clearly detected.

Materials	Fe at.%	C at.%	N at.%	O at.%
Fe-N-C NH ₃	0.26	82.9	7.1	9.7
Fe-N-C Ar	0.7	85.5	7.4	6.5
Pure NC	—	87.5	6.3	6.3

Table S2 XPS Fitting parameters for Fe-N-C NH₃, Fe-N-C Ar and pure NC.

Sample		Fe-N-C NH ₃	Fe-N-C Ar	Pure NC
C 1s	C-C	Position (eV)	284.4	284.3
		FWHM (eV)	1.2	1.1
		Relative area (%)	43	42
	C-N	Position (eV)	285.3	285.1
		FWHM (eV)	2.7	2.5
		Relative area (%)	44	44
	C-O	Position (eV)	289	288.6
		FWHM (eV)	3.5	3.7
		Relative area (%)	14	13
N 1s	Pyridinic N	Position (eV)	398.1	398.1
		FWHM (eV)	1.4	1.5
		Relative area (%)	35	36
	Pyrrolic N	Position (eV)	400.2	400.2
		FWHM (eV)	2.8	2.9
		Relative area (%)	56	54
	Oxidized N	Position (eV)	403.9	404.3
		FWHM (eV)	3.7	3.7
		Relative area (%)	9	11
O 1s	C=O	Position (eV)	531.4	531.4
		FWHM (eV)	2.7	2.8
		Relative area (%)	82	83
	C-OH	Position (eV)	533.1	533.2
		FWHM (eV)	3.6	3.7
		Relative area (%)	18	17
	Fe 2p	Position (eV)	710.1	710.4
		FWHM (eV)	3.7	5.2
		Relative area (%)	29	53
Fe 2p	Fe (II) satellite	Position (eV)	714.6	715.4
		FWHM (eV)	6.4	2.7
		Relative area (%)	27	6
	Fe 2p _{1/2}	Position (eV)	724.2	723.3
		FWHM (eV)	9.5	10.7
		Relative area (%)	44	41

Table S3 Double layer capacitance (C_{dl}) and corresponding allometric fit parameters of Fe-N-C materials with relevant data sets.

Catalyst	C_{DL}/mF anodic	α anodic	R^2 anodic	C_{DL}/mF cathodic	α cathodic	R^2 cathodic	C_{DL}/mF average
Fe-N-C NH ₃	0.9263	0.9139	0.9992	0.9089	0.9052	0.9996	0.9176
Fe-N-C Ar	0.3733	0.9351	0.9999	0.3645	0.9402	1.0000	0.3689
Pure NC	0.6246	0.8951	0.9999	0.6136	0.8911	0.9995	0.6191
Pt/C 20%	0.2593	0.9151	0.9990	0.2993	0.8751	0.9996	0.2793

Table S4 Performance comparison of some recently reported PGMs-free Fe-based catalysts for ORR.

Catalyst	Electrolyte	Catalyst loading (mg cm ⁻²)	Scan rate (mV s ⁻¹)	E ₋₁ *(V vs RHE)	number of electron transfer (n)	Reference
Fe-N-C NH ₃	0.1M KOH	0.20	5 mV s ⁻¹	0.89	3.98	This work
Fe-N/P-C-700	0.1M KOH	0.60	5 mV s ⁻¹	0.91	3.94	[1]
Zn/Fe2-N-C	0.1 M KOH	0.341	5 mV s ⁻¹	0.88	3.96	[2]
FePx/Fe-N-C/NPC	0.1M KOH	0.21	10 mV s ⁻¹	0.93	3.90	[3]
Fe1-HNC-500-850	0.1M KOH	0.20	5 mV s ⁻¹	0.89	NA	[4]
Fe-SAs/NSC	0.1M KOH	0.20	10 mV s ⁻¹	0.87	3.96	[5]
Fe/OES	0.1M KOH	0.40	5 mV s ⁻¹	0.88	3.90	[6]
Fe-N-C HNSs	0.1M KOH	0.255	5 mV s ⁻¹	0.91	3.98	[7]

Supplementary References

1. K. Yuan, D. Lützenkirchen-Hecht, L. Li, L. Shuai, Y. Li, R. Cao, M. Qiu, X. Zhuang, M. K. H. Leung, Y. Chen, and U. Scherf, *J. Am. Chem. Soc.* **142**, 2404 (2020).
2. J. Xue, Y. Li, and J. Hu, *J. Mater. Chem. A* **8**, 7145 (2020).
3. Q. Qin, H. Jang, P. Li, B. Yuan, X. Liu, and J. Cho, *Advanced Energy Materials* **9**, 1803312 (2019).
4. X. Zhang, S. Zhang, Y. Yang, L. Wang, Z. Mu, H. Zhu, X. Zhu, H. Xing, H. Xia, B. Huang, J. Li, S. Guo, and E. Wang, *Advanced Materials* **32**, 1906905 (2020).
5. J. Zhang, Y. Zhao, C. Chen, Y.-C. Huang, C.-L. Dong, C.-J. Chen, R.-S. Liu, C. Wang, K. Yan, Y. Li, and G. Wang, *J. Am. Chem. Soc.* **141**, 20118 (2019).
6. C.-C. Hou, L. Zou, L. Sun, K. Zhang, Z. Liu, Y. Li, C. Li, R. Zou, J. Yu, and Q. Xu, *Angewandte Chemie International Edition* **59**, 7384 (2020).
7. Y. Chen, Z. Li, Y. Zhu, D. Sun, X. Liu, L. Xu, and Y. Tang, *Advanced Materials* **31**, 1806312 (2019).